

Anotation

There is developing of a system of ultrasonic microscopy in this project. As a control object performs electronic integrated circuits. Flaw can be used in steel plants, which produce beams of this type.

The project aims to develop an ultrasonic microscope that works at the operating frequency of 100 MHz and provides reliability of control up to 99%. This device can detect internal defects of a chip structure. Microscope uses acoustic lens as the sensor, whose design is developing in this project. Based on the measured signals, device builds the image of the object with resolution of 552 PPI.

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